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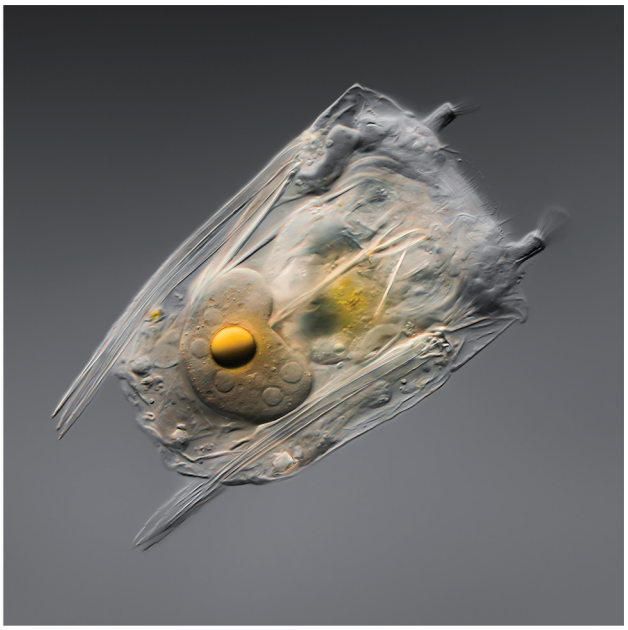
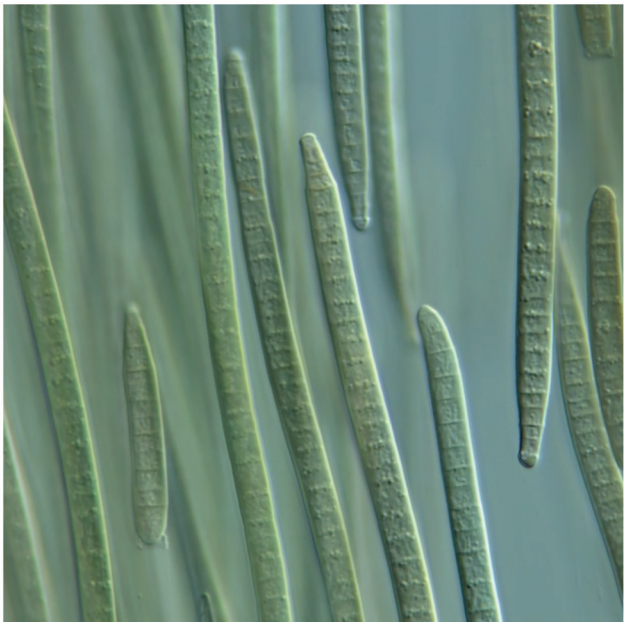
Microscopy TODAY





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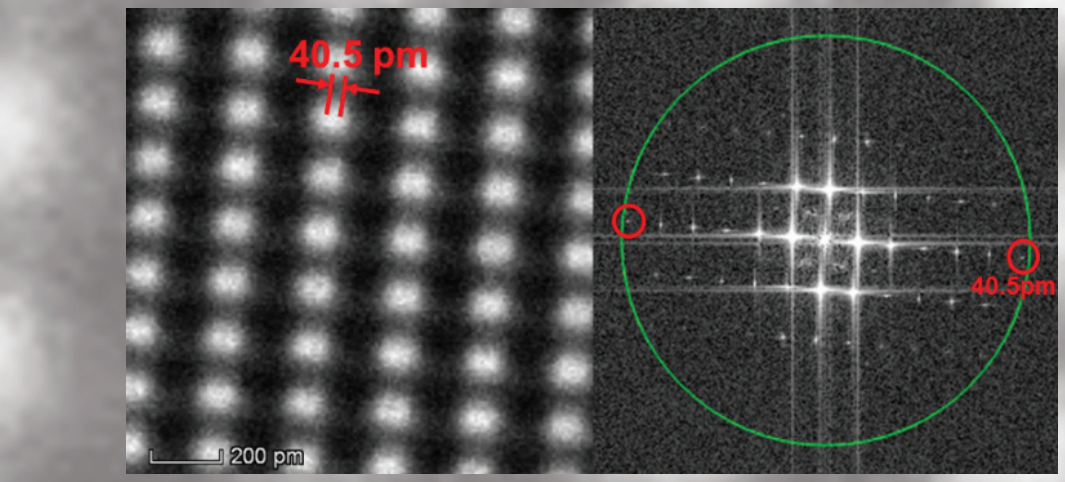

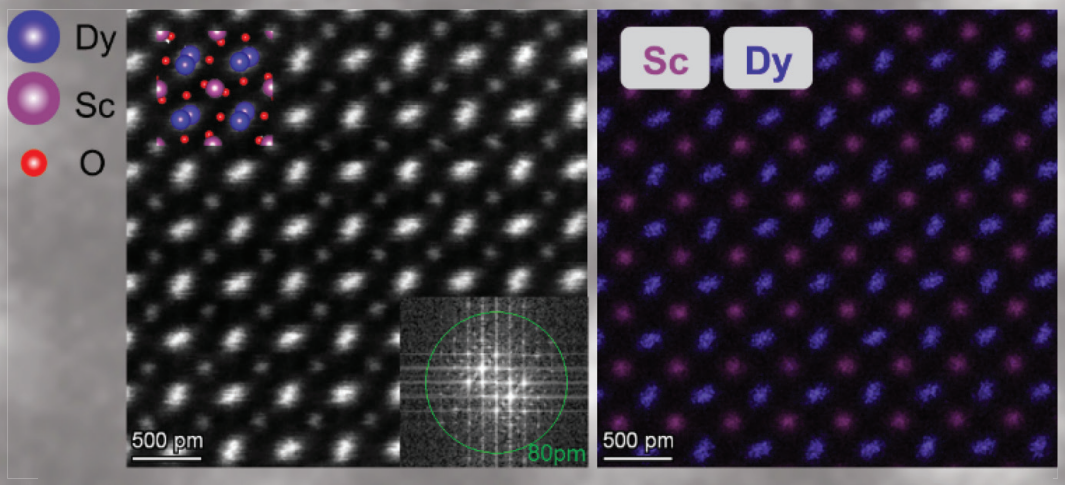

Figure 1a (top): HAADF (DCFI) STEM image of GaN [212] at 300 kV showing 40.5 pm Ga-Ga dumbbell splitting and 39 pm resolution in the FFT on a wide gap (S-TWIN) pole piece.

Figure 1b (bottom): $DyScO_3$ specimen investigated with a Spectra 200 S/TEM. The combined ultra-high brightness of the X-CFEG, resolving power of the S-CORR and large solid angle (1.76 Sr) of the Dual-X detectors results in high signal to noise ratio, atomic resolution, raw and unfiltered EDX maps that can be collected with up to 90 pm resolution. *Sample courtesy: Professor L.F. Kourkoutis, Cornell University.*

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Winners of the 2019 *Microscopy Today* Micrograph Awards. Clockwise from upper left: 1st Prize in the Published category, 1st Prize in the Open category, 1st Prize in the Video category, and the winner of the People's Choice Award.

See article on page 12.

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